

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10661503	HIKAWA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	PHILIP C LEE	2152

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
709	106,224	7/18/08	/pl/
707	10	7/18/08	/pl/
717	102	7/18/08	/pl/

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
keywords search in EAST	7/18/08	/pl/
keywords search in 709/106,224; 707/10; 717/102 in EAST	7/18/08	/pl/

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>